


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/634,562	FERNANDEZ ET AL.	
	Examiner	Art Unit	
	Quynh H. Nguyen	2614	

SEARCHED			
Class	Subclass	Date	Examiner
379	202.01	1/17/2007	QN
709	204 205	1/17/2007	QN
370	260	1/17/2007	QN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
searched: East, USPGPub, USPAT	1/17/2007	QN
Inventor searched through PALM database	1/17/2007	QN